

<b>Notice of References Cited</b>	Application/Control No. 10/534,458		Applicant(s)/Patent Under Reexamination YONEZAWA ET AL.	
	Examiner LEE D. WILSON		Art Unit 3723	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,095,509 A	08-2000	Yonezawa, Keitaro	269/309
*	B	US-6,024,354 A	02-2000	Yonezawa, Keitaro	269/309
*	C	US-6,604,738 B2	08-2003	Haruna, Yosuke	269/309
*	D	US-2006/0055099 A1	03-2006	Haruna, Yosuke	269/309
*	E	US-2006/0049568 A1	03-2006	Yonezawa et al.	269/309
*	F	US-2006/0033255 A1	02-2006	Yonezawa et al.	269/309
*	G	US-2006/0049569 A1	03-2006	Yonezawa, Keitaro	269/309
*	H	US-6,527,266 B1	03-2003	Yonezawa et al.	269/309
*	I	US-2004/0046302 A1	03-2004	Bernhard et al.	269/309
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

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